

<b>Notice of References Cited</b>	Application/Control No. 10/840,192	Applicant(s)/Patent Under Reexamination FUJIKAWA ET AL.	
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**U.S. PATENT DOCUMENTS**

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**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 1767491 A1	03-2007	EP	-----	-----
	O	JP 2003077922	03-2003	JP	-----	-----
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